



## Product/Process Change Notice - PCN 13\_0249 Rev. A

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Material Report). Any issues with this PCN or requirements to qualify the change (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

*Note: Revised fields are indicated by a red field name. See Appendix B for revision history.*

**PCN Title:** Assembly Transfer of Select 2x3mm LFCSP Products using 8900 Die Attach to STATS ChipPAC China

**Publication Date:** 14-Jul-2014

**Effectivity Date:** 18-May-2014 *(the earliest date that a customer could expect to receive changed material)*

### Revision Description:

Update to include Qualification Report Summary

### Description Of Change

ADI is transferring to subcontractor STATS ChipPAC China for the assembly of select 2x3mm LFCSP products using Ablestik 8900 die attach. The package outline dimensions and BOM of each product will be maintained.

### Reason For Change

ADI is transferring to STATS ChipPAC China due to the closure of STATS ChipPAC Malaysia at the end of 2014.

ADI's assembly subcontractors manufacture products using Analog Devices specified manufacturing flows, materials, process controls and monitors, ensuring the same level of quality and reliability on products they receive from the new site.

### Impact of the change (positive or negative) on fit, form, function & reliability

The transfer will have no impact on the form, fit, function and reliability of the devices.

### Product Identification *(this section will describe how to identify the changed material)*

The parts that will be assembled after the transfer will be identified by assembly lot and the country of origin.

### Summary of Supporting Information

Qualification has been performed per ADI0012, Procedure for Qualification of New or Revised Processes. See attached Qualification Results Summary.

### Supporting Documents

**Attachment 1:** Type: Qualification Results Summary

ADI\_PCN\_13\_0249\_Rev\_A\_Qualification\_Results\_Summary.pdf

**Attachment 2:** Type: Detailed Change Description

ADI\_PCN\_13\_0249\_Rev\_A\_BOM.pptx

**For questions on this PCN, send email to the regional contacts below or contact your local ADI sales representative**

<b>Americas:</b> PCN_Americas@analog.com	<b>Europe:</b> PCN_Europe@analog.com	<b>Japan:</b> PCN_Japan@analog.com
		<b>Rest of Asia:</b> PCN_ROA@analog.com

**Appendix A - Affected ADI Models****Existing Parts - Product Family / Model Number (2)**

AD590 / AD590JCPZ-R5	AD590 / AD590JCPZ-RL7			
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### Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	12-Nov-2013	18-May-2014	Initial Release
Rev. A	14-Jul-2014	18-May-2014	Update to include Qualification Report Summary

Analog Devices, Inc.

DocId:2986 Parent DocId:None Layout Rev:7

**Qualification Results Summary for  
LFCSP Package with Non-conductive Die Attach Epoxy  
at STATS ChipPAC China (SCC)**

QUALIFICATION RESULTS			
Test	Conditions	Sample Size	Result
Highly Accelerated Stress Test (HAST)*	JEDEC JESD22-A110	3 x 77	<b>PASS</b>
Temperature Cycle (TC)*	JEDEC JESD22-A104	3 x 77	<b>PASS</b>
Autoclave (AC)*	JEDEC JESD22-A102	3 x 77	<b>PASS</b>
Solder Heat Resistance (SHR)*	JEDEC/IPC J-STD-020	3 x 11	<b>PASS</b>
High Temperature Storage Life (HTSL)	JEDEC JESD22-A103	1 x 77	<b>PASS</b>
Field Induced Charged Device Model (FICDM)	JEDEC JESD22-C101	3/Voltage	<b>PASS ±1250V</b>

\*Preconditioned per JEDEC/IPC J-STD-020